


<b>Search Notes</b>  	<b>Application/Control No.</b>  10669259	<b>Applicant(s)/Patent Under Reexamination</b>  TAKAHASHI ET AL.
	<b>Examiner</b>  Hung, Yubin	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	166,233,248,250	3/20/07	YH
345	395.1,403.1	3/20/07	YH
375	240.18,240.19,240.2	3/20/07	YH
708	203	3/20/07	YH

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Text search (USPGPUB, USPAT, EPO, JPO, DERWENT, IBM-TDB)	3/20/07	YH
ACM	3/20/07	YH
SPIE	3/20/07	YH
IEEE Xplore	3/20/07	YH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner